

INFORMATION DISCLOSURE CITATION IN AN APPLICATION						ATTY. DOCKET NO. 57810-093		SERIAL NO. 16/806,276		
(PTO-1449)						APPLICANT Hideaki FUJIWARA, et al.				
						FILING DATE March 23, 2004		GROUP 2813		
U.S. PATENT DOCUMENTS										
EXAMINER'S INITIALS		CITE NO.	Document Number Number-Kind Code(s) (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document			Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
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FOREIGN PATENT DOCUMENTS										
EXAMINER'S INITIALS		CITE NO.	Foreign Patent Document Country Codes - Number & Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines Where Relevant Figures Appear		Translation	
DB			JP P2002-94058A	03/29/2002	TOSHIBA CORP				Yes	No
									(Japan w/English Abstract)	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)										
EXAMINER'S INITIALS		CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.							
DB			Brian DOYLE, et al. "Transistor Elements for 30nm Physical Gate Lengths and Beyond", Intel Technology Journal, Vol. 6, Issue 2, May 16, 2002, ISSN 1535766X							
EXAMINER		DATE CONSIDERED								
D. Delmar		1-6-05								

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